

ESA & CNES Final Presentations : Space Environments and Radiation Effects on EEE components

Wednesday, 8 March 2017

Radiation Effects on EEE components: CNES - Newton2 (09:30 - 13:00)

time	[id] title	presenter
09:30	[44] Impact of the detector definition on the Reverse Monte Carlo calculation result	Mr POURROUQUET, Pierre
09:50	[45] Comparison of TNID calculation methods	Mr POURROUQUET, Pierre
10:10	[66] Introduction to "CNES Radiation Effects on EEE components" Session	Mrs BEZERRA, Françoise
10:15	[46] Electron SEE- background and current status	Mr ECOFFET, Robert
10:35	[47] Proton direct ionisation	Mr SUKHASEUM, Nicolas
11:00	Coffee break	
11:20	[48] TRADCARE: tool for SEE prediction in a radiation environment	Mr POURROUQUET, Pierre
11:45	[49] Recoil atom flux calculation in electronic components by Monte Carlo method	Mr POURROUQUET, Pierre
12:05	[50] Weakened Cell /stuck bit	Mrs BEZERRA, Françoise Ms CHATRY, Natalie
12:25	[51] Flash TID/SEE	Mr SUKHASEUM, Nicolas
12:45	[52] Test facilities	Mrs BEZERRA, Françoise

Radiation Effects on EEE components: ESA (TEC-QEC) - Newton2 (14:00 - 18:05)

time	[id] title	presenter
14:00	[12] Introduction	ZADEH, Ali
14:10	[3] Displacement Damage test guideline	Mr NUNS, Thierry
14:30	[6] Validation of NIEL for high energy (> 1MeV) electrons in Silicon	Mr NUNS, Thierry
14:50	[67] _____ schedule updated to include 20min delay	
15:10	[7] Verification of Co-60 TID testing representativeness for EEE components flown in the Jupiter environment	Mr PINTO, Marco
15:30	[8] Part to part and lot to lot variability study of TID effects in bipolar linear devices	Mr SUKHASEUM, Nicolas
15:50	Coffee Break	
16:10	[9] Radiation characterization of European EEE components for space applications	Dr GARCIA, Pierre
16:40	[10] Test methods for SEE evaluations of ADCs and DACs	Mr GUERRE, françois-xavier
	- [1] Dummy entry	
17:00	[15] TID testing of state of the art NAND flash memories	Dr TANIOS, Bendy

17:30	[13] Heavy-Ion Micro Beam and Simulation Study of a Flash-Based FPGA Microcontroller Implementation	Mr URBINA ORTEGA, Carlos
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Thursday, 9 March 2017

Radiation Effects on EEE components: ESA (TEC-QEC) - Newton2 (09:00 - 13:20)

time	[id] title	presenter
09:00	[26] Irradiation characterisation of 2D imaging devices, memories and FPGAs for future ESA missions	Mr LE GOULVEN, ENOAL
09:20	[35] Radiation Evaluation of Digital Isolators	Dr WIND, Michael
09:40	[32] Survey of total ionising dose tolerance of power bipolar transistors and Silicon Carbide devices for JUICE	Dr STEFFENS, Michael
10:00	[34] Total Ionizing Dose influence on the single event effect sensitivity of active EEE components	Mr SALVY, Lionel
10:20	[36] ESA supported Radiation Facility	Dr KETTUNEN, Heikki Mr STANDAERT, Laurent Dr HAJDAS, Wojtek
10:50	Coffee Break	
11:10	[38] Risk assessment of SEE events due to high energy electrons during the JUICE mission	Mr SUKHASEUM, Nicolas
11:30	[39] Single Event Burnout testing of high power schottky diodes	Dr GARCIA, Pierre
12:00	[40] Re-issue Radiation Characterisation of GaAs power devices in support of European Radiation Hardness	Mr CHUAN, Jeffrey
12:20	[42] Laser Study of SETs in 65nm Bulk Technology	Mr EVANS, Adrian
12:40	[41] Comprehensive SEE Component Qualification	Mr EVANS, Adrian